## Notice of References Cited Application/Control No. 10/671,965 Examiner Chuck Huynh Applicant(s)/Patent Under Reexamination TAJIMA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,714,785	03-2004	Han, Chung-Seok	455/440
*	В	US-5,602,903	02-1997	LeBlanc et al.	455/456.2
*	С	US-6,587,781	07-2003	Feldman et al.	701/117
*	D	US-6,801,511	10-2004	Park, Ji-Hoon	370/331
*	E	US-6,721,567	04-2004	Wang et al.	455/440
*	F	US-6,611,688	08-2003	Raith, Alex Krister	340/992
*	G	US-6,587,689	07-2003	Panasik, Carl M.	455/440
*	Н	US-6,385,454	05-2002	Bahl et al.	455/450
*	1	US-6,052,598	04-2000	Rudrapatna et al.	455/456.1
*	J	US-5,465,389	11-1995	Agrawal et al.	455/437 🚣
*	К	US-5,572,221	11-1996	Marlevi et al.	342/452
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	a					
	R					
	S					
	T	-				

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.